



ETEC 2007

ETEC 2007 TEST SUITE

For the Terminal Integration Process (TIP) and more

- Following an implementation process defined by MasterCard® Worldwide.
- For the migration to MasterCard M/Chip 4 (contact and contactless)
- Pass the approval process “Terminal Integration Process” (TIP) and Network Interface Validation (NIV).
- Get the MasterCard letter of approval, which proves that your application can perform transactions according to EMV specifications and MasterCard requirements.
- “Terminal Integration Process” (TIP) is based on MasterCard ETEC test cards, provided in 2 subsets of chip/magnetic stripe test cards
- Designed to test EMV regression functions of the payments terminal applications and to test against MasterCard Functional Architecture
- Designed for banks, payment systems, smart card/terminal vendors and integrators, the Smartspy enables you to rapidly analyze failures and enable quick debugging analysis to speed up your time to market.

For Chip/Magnetic stripe test cards

- ETEC Subset 1: Test international interoperability of MasterCard branded cards
- ETEC Field Interoperability Subset: Reproduce field interoperability issues
- ETEC Subset 3: Validate the dual-message interface between the acquirer host and MasterCard network systems
- ETEC Subset 5: Test the dual-message acquirer host PIN management application interface to MasterCard’s network
- ETEC Maestro UK subset: Ensure that your terminal is able to manage the ICC technology according to UK Domestic Maestro requirements
- ETEC Subset 13 Sweden: Test and validate during the network interface your SWEDEN Domestic dual-message acquirer host debit/credit application interface(s) MasterCard network systems.

- A fast efficient method to meet your project’s migration objectives.
- ETEC subsets 6, 7 and 8 are used to perform preapplicative testing prior to Type Approval Testing
- A complete migration test tool using test cards!

FIME, as a participant of the MasterCard Vendor Program, is the official distributor of the ETEC test tool for MasterCard Worldwide.

For more Information, please contact:

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MasterCard.
Vendor Program
2008 Participant



FIME
Enabling Business with
IC Testing Solutions

For MasterCard PayPass™

- ETEC Subset 6 MasterCard (PayPass – Mag Stripe): Test and Validate during network interface your dual-message acquirer host credit application interface(s) to MasterCard network systems.
- ETEC Subset 6 Debit MasterCard: Test and Validate during network interface your dual-message acquirer host Debit application interface(s) to MasterCard network systems.
- ETEC Subset 7 (PayPass – M/Chip NIV): Upgrade your M/Chip based systems to also support PayPass M/Chip operations
- ETEC Subset 8 (PayPass – M/Chip TIP): Ensure that PayPass –M/Chip terminals manage PayPass technology according to MasterCard requirements
- ETEC Maestro PayPass Subset: Ensure compliance of *PayPass - M/Chip* terminals with Maestro *PayPass* requirements.

Acquirer tests Subsets ↓		CONTACT				CONTACTLESS				
		TIP without Clearing tests	TIP + Clearing tests (as per Global Operation Bulletin, October 2007)	NIV	NIV PIN Management	NIV + TIP PayPass MagStripe	TIP MasterCard PayPass M/Chip	TIP Maestro PayPass M/Chip	TIP PayPass M/Chip MasterCard + Maestro	NIV PayPass M/Chip
CONTACT	Subset 1 V2007A	✓	✓							
	Optional Clearing cards		✓							
	Field Interop V2007A	✓	✓							
	Subset 3			✓						
	Subset 5				✓					
CONTACTLESS	Subset 6 (Credit) V1.0 (Magstripe)					✓	✓		✓	
	Subset 6 (Debit MasterCard) V1.0 (Magstripe)					✓*				
	Subset 7									✓
	Subset 8						✓		✓	
	Maestro PayPass Subset							✓	✓	